

Welcome to Galaxy Examinator reports

Date: Tue Sep 3 11:52:58 2024

Product : LotID :

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Histogram of Tests

Pareto lists: Tests Cp , Tests Cpk , Failures , Failure Signatures , Software Bin , Hardware Bin

Wafermaps & Strip Maps
Bins (Software, Hardware)

Message Log: Empty

Global information and options



Tests Statistics

Test	Name	Type	Low L.	High L.	Source	Execs	Fails	Mean	Sigma	Ср	Cpk	Yield
<u>1</u>	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	20	0	0.14555	0.00190498	n/a .	n/a .	100.00 %
<u>2</u>	Functional_T5 p50 19.e128	P	n/a .	n/a .	Samples	20	0	3.2824	0.00218608	n/a .	n/a .	100.00 %
<u>4</u>	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	20	0	234.4 ns	1.66702 ns	20.00	16.88	100.00 %
<u>5</u>	Functional_T6 p50 19.e128	P	150 ns	350 ns	Samples	20	0	244.5 ns	1.7014 ns	19.59	18.51	100.00 %
<u>6</u>	Functional_T6 A8 0	P	1 ns	100 ns	Samples	20	0	10.1 ns	2.63379 ns	6.26	1.15	100.00 %
<u>7</u>	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	20	0	3.2821 V	0.0020494 V	n/a .	n/a .	100.00 %
<u>8</u>	Functional_T7 p53 19.e135	P	n/a .	n/a .	Samples	20	0	0.1392	0.00230788	n/a .	n/a .	100.00 %
<u>12</u>	Functional_T8 A8 0	P	1 ns	20 ns	Samples	20	2	154.76 ns	662.175 ns	0.0048	-0.0678	90.00 %
<u>786000</u>	Soft_Bin parameter	_	n/a .	n/a .	Samples	20	0	1	0	n/a .	n/a .	100.00 %
<u>786001</u>	Hard_Bin parameter	_	n/a .	n/a .	Samples	20	0	1	0	n/a .	n/a .	100.00 %
<u>786002</u>	Die_X parameter	_	n/a .	n/a .	Samples	20	0	1.5	1.14708	n/a .	n/a .	100.00 %
<u>786003</u>	Die_Y parameter	_	n/a .	n/a .	Samples	20	0	2	1.45095	n/a .	n/a .	100.00 %
<u>786004</u>	Test_Time parameter	_	0.0 sec	n/a .	Samples	20	0	2.43565 sec	0.44072 sec	n/a .	1.84	100.00 %
<u>786006</u>	Testing_Site parameter	_	n/a .	n/a .	Samples	20	0	0	0	n/a .	n/a .	100.00 %
<u>786007</u>	Part_ID parameter	-	n/a .	n/a .	Samples	20	0	10.5	5.91608	n/a .	n/a .	100.00 %

Tests Statistics 2/24



Test

Name Functional_T5 p50 19.e128

Test type Parametric Low limit n/a . High limit n/a .

Exec / Fails 20 / 0 (0.00%)

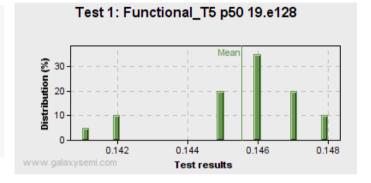
Mean 0.14555

Sigma 0.00190498

Range 0.007

Cp / Cpk n/a . / n/a .

Samples 20



Test

Name Functional_T5 p50 19.e128

Test type Parametric
Low limit n/a .
High limit n/a .

Exec / Fails 20 / 0 (0.00%)

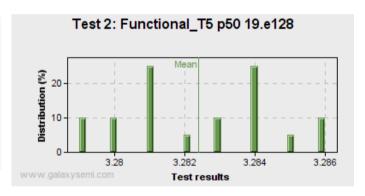
Mean 3.2824

Sigma 0.00218608

Range 0.00699997

Cp / Cpk n/a . / n/a .

Samples 20



Histogram of Tests 3/24

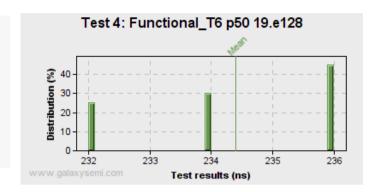
Test

Name Functional_T6 p50 19.e128

Test type Parametric Low limit 150 ns High limit 350 ns Exec / Fails 20 / 0 (0.00%) Mean 234.4 ns Sigma 1.66702 ns Range 4 ns

Cp / Cpk 20.00 / 16.88

Samples 20

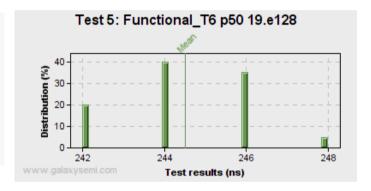




Functional_T6 p50 19.e128

Test type Parametric Low limit 150 ns High limit 350 ns Exec / Fails 20 / 0 (0.00%) Mean 244.5 ns Sigma 1.7014 ns 5.99999 ns Range Cp / Cpk 19.59 / 18.51

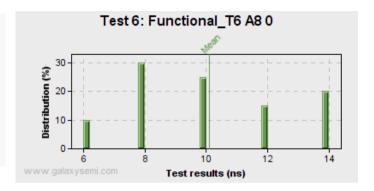
Samples 20



Histogram of Tests 4/24 Test <u>6</u>

Name Functional_T6 A8 0

Test type Parametric Low limit 1 ns High limit 100 ns 20 / 0 (0.00%) Exec / Fails Mean 10.1 ns Sigma 2.63379 ns Range 8 ns Cp / Cpk 6.26 / 1.15 Samples 20



Test

Name Functional_T7 p53 19.e135

Test type Parametric
Low limit n/a .
High limit n/a .

Exec / Fails 20 / 0 (0.00%)

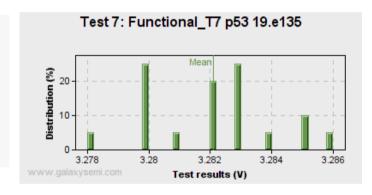
Mean 3.2821 V

Sigma 0.0020494 V

Range 0.0079999 V

Cp / Cpk n/a . / n/a .

Samples 20



Histogram of Tests 5/24

Test 8

Name Functional_T7 p53 19.e135

 $\begin{tabular}{lll} Test type & Parametric \\ Low limit & n/a \ . \\ High limit & n/a \ . \\ \end{tabular}$

Exec / Fails 20 / 0 (0.00%)

Mean 0.1392

Sigma 0.00230788

Range 0.009

Cp / Cpk n/a . / n/a .

Samples 20



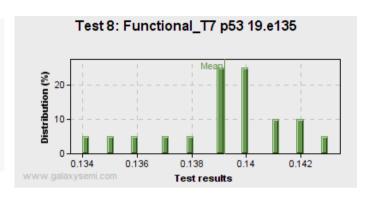
Name Functional_T8 A8 0

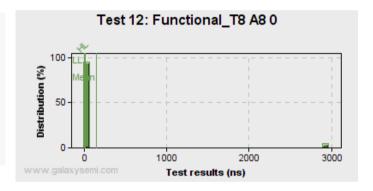
Test type Parametric
Low limit 1 ns
High limit 20 ns

Exec / Fails 20 / 2 (10.00%)
Mean 154.76 ns
Sigma 662.175 ns
Range 2970 ns

Cp / Cpk 0.0048 / -0.0678=> Warning: Process is over the high limit

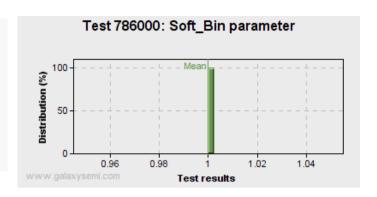
Samples 20



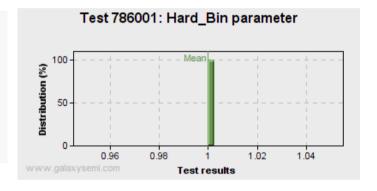


Histogram of Tests 6/24

Test 786000 Name Soft_Bin parameter Test type Low limit n/a . High limit n/a . Exec / Fails 20 / 0 (0.00%) Mean Sigma 0 Range 0 Cp / Cpk n/a . / n/a . Samples 20



Test	<u>786001</u>
Name	Hard_Bin parameter
Test type	<mark>-</mark>
Low limit	n/a .
High limit	n/a .
Exec / Fails	20 / 0 (0.00%)
Mean	1
Sigma	0
Range	0
Cp / Cpk	n/a . / n/a .
Samples	20



Histogram of Tests 7/24

Test <u>786002</u>

Name Die_X parameter

Test type – Low limit n/a. High limit n/a.

Exec / Fails 20 / 0 (0.00%)

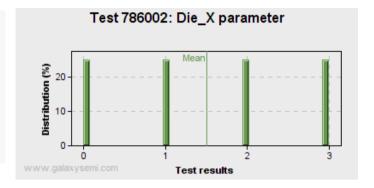
 Mean
 1.5

 Sigma
 1.14708

 Range
 3

 Cp / Cpk
 n/a . / n/a .

Samples 20



Test <u>786003</u>

Name Die_Y parameter

Test type – Low limit n/a . High limit n/a .

Exec / Fails 20 / 0 (0.00%)

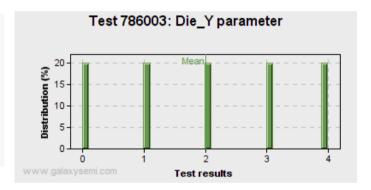
 Mean
 2

 Sigma
 1.45095

 Range
 4

Cp / Cpk n/a . / n/a .

Samples



Histogram of Tests 8/24

Test 786004

Name Test_Time parameter

Test type Low limit

0.0 sec

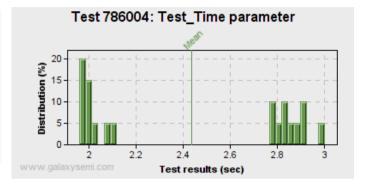
High limit

Test

n/a .

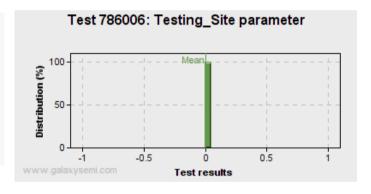
Exec / Fails 20 / 0 (0.00%) Mean 2.43565 sec Sigma 0.44072 sec Range 1.041 sec Cp / Cpk n/a . / 1.84

Samples 20

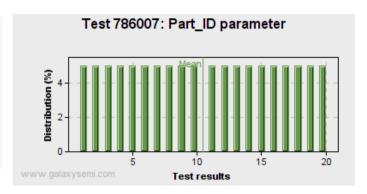




Sigma 0 0 Range Cp / Cpk n/a . / n/a . Samples 20



Histogram of Tests 9/24 Test 786007 Part_ID parameter Name Test type Low limit n/a . High limit n/a . Exec / Fails 20 / 0 (0.00%) Mean 10.5 Sigma 5.91608 19 Range Cp / Cpk n/a . / n/a . Samples 20





Test	Name	Ср	Test Cp Chart
<u>12</u>	Functional_T8 A8 0	0.0048	

Shows all Cp <= 1.7 (Defined in Options, section 'Pareto/Define Cp cut-off limit')

Pareto of Tests Cp 10/24



Test	Name	Cpk	Test Cpk Chart
<u>12</u>	Functional_T8 A8 0	-0.0678	
<u>6</u>	Functional_T6 A8 0	1.15	

Shows all Cpk <= 1.3 (Defined in Options, section 'Pareto/Define Cp cut-off limit')

Pareto of Tests Cpk 11/24



Test	Name	Failing Bin	Failures count	Yield Loss	Fail contribution	Test Fail rate	Failures Chart
<u>12</u>	Functional_T8 A8 0	-	2	10.0 %	n/a	10.0 %	
_	Cumul. of failures	-	2	10.0 %	0.0 %	10.0 %	

- -- Yield loss: number of failed test executions / number of parts
- -- Fail contribution: number of failed test executions / number of parts failed
- -- Test Fail rate: number of failed test executions / number of test executions

Pareto of Tests failures 12/24



Pareto of Functional Failure Signatures (pins tested in parallel)

Total devices tested: **20**Total patterns detected: **1**

Fail count	% of failures	% of tested	Functional Failure signatures (tested pins failing together)
2	100.00 %	10.00 %	% Functional_T8 A8 0 (Test 12)
2	100 %	-	- Total failures detected

Shows first 25 % of the failure signatures (Defined in Options, section 'Pareto/Define Failure Signatures cut-off limit')



Pareto of Parametric Failure Signatures (tests failing concurrently)

No Parametric failure signature detected



Pareto of Software Bins 14/24



Pareto of Hardware Bins 15/24



Show Software bins

20 **Devices tested (with retests)**

Total physical parts tested 20 (only applies to Wafermaps)



Top 10 Software Binning	1
Color	
Pass/Fail	P
Percentage	100.0%
Total count	20

List of Individual Maps 16/24 Map style STRIP map (parts tested are PACKAGED DEVICES!)

Total physical

parts tested

Parts processed All Data / parts (any Bin)

20

Data from Sites All sites

 Strip started
 Tue Sep 03 23:41:58 2024

 Strip ended
 Tue Sep 03 23:48:18 2024

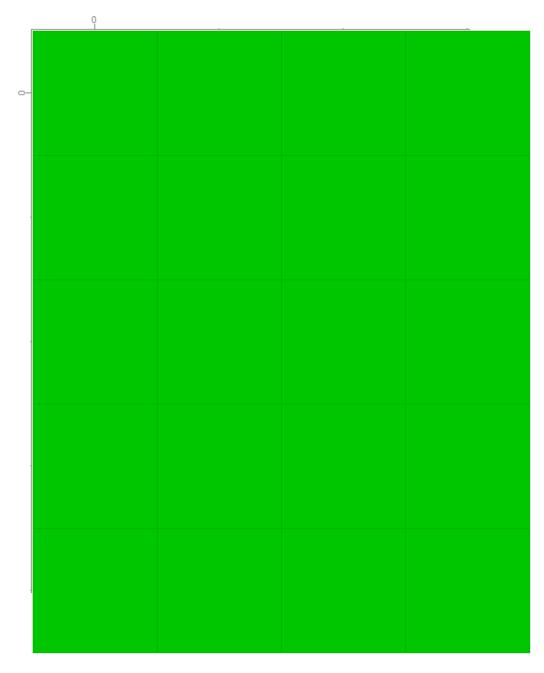
Wafer tested in 6 minutes 20 seconds

Average device test time

19.000 sec.

Map dimensions LowX=0, LowY=0, HighX=3, HighY=4

List of Individual Maps 17/24



List of Individual Maps 18/24



List of Individual Maps 19/24



Software Binning	Bin Name	Pass/ Fail	Total count	Percentage	Software Binning Chart
1	-	P	20	100.0 %	
All PASS Bins	All PASS Bins	P	20	100.0 %	
ALL Bins	ALL Bins	_	20	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)

Software Binning Summary 20/24



<u>Hardware</u> <u>Binning</u>	Bin Name	Pass/ Fail	Total count	Percentage	Hardware Binning Chart
1	-	P	20	100.0 %	
All PASS Bins	All PASS Bins	P	20	100.0 %	
ALL Bins	ALL Bins	-	20	100.0 %	

Hint: From the 'Options' tab in the 'Binning' section, you can configure how to compute the binning (from summary or samples)



No log message to report



Report from	Teradyne–Examinator–Pro+ – V8.1.5 – www.galaxysemi.com
Report created	Tue Sep 03 11:52:58 2024
Data processed	30.4 KB (31127 bytes)
Processing time	0.56 second
Processing speed	54.8 KB/sec
Examinator expires	Sun Sep 3 2034
(null)	-
File name	C:/Users/rahmana/OneDrive – Teradyne/Desktop/New Hire/New Hire Tech/UFP New Hire Train/Project 1/i8243/results_v1_30loop.std
Tests mapping file	n/a

Global Information 21/24

Start time	Setup time	Tue Sep 03 23:36:42 2024
End time Tue Sep 03 23:48:18 2024 Test duration 6 minutes 20 seconds Product n/a Program rahmanu_i8243_p1.igxl Revision n/a Sub—Lot n/a WaferID n/a VareTime Council on Info All Data / parts (any Bin) Data from Sites All Sites Test time (GOD parts) 2.436 sec. (excludes tester idle time) Test time (ALL parts) 2.436 sec. (excludes tester idle time) Average test time 19.000 sec. / device (includes tester idle time between parts) Total parts tested 20 − Includes parts retested (if any) Bad parts (Yield loss) 0 (0.00%) − Includes parts retested (if any) Bards aborted 0 (0.00%) − Includes parts retested (if any) Parts retested n/a Starts aborted 0 (0.00%) − Includes parts retested (if any) Tester type UltraFLEXplus Station 1 Tester type UltraFLEXplus Station 1 Part type n/a Operator rahmana Exec. ty	•	-
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Per_freq n/a Spec_name n/a Spec_version n/a	Aux_file	n/a
Spec_name n/a Spec_version n/a	Package type	n/a
Spec_version n/a	Per_freq	n/a
	Spec_name	n/a
Family ID n/a	Spec_version	n/a
	Family ID	n/a

Global Information 22/24

Date code	n/a
Design Rev	n/a
Facility ID	n/a
Floor ID	n/a
Proc ID	n/a
Flow ID	n/a
Setup ID	n/a
Eng ID	n/a
ROM code	n/a
Serial #	n/a
Super user name	n/a
Handler/Prober	n/a
(null)	-
Site details	Site# 0

Global Information 23/24



Test# policy	Never merge tests with identical test number if test name not matching
Data Cleaning	None (keep all data)
Statistics computation	From samples data (if any), otherwise from summary
Binning computation	From summary data (if any), otherwise from samples
Cp,Cpk computation	Use standard Sigma formula
Mean drift formula	Percentage of value drift

Global Options 24/24